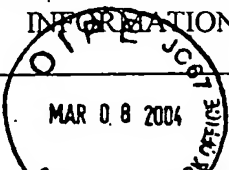







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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT David BERMAN, et al.	EXAMINER <del>AA</del> Kao
	FILING DATE October 20, 2003	GROUP ART UNIT <del>AA</del> 2882






## U.S. PATENT DOCUMENTS

Examiner's initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	5,740,226	Apr. 1998	Komiya, et al.			
	AB	5,619,548	Apr. 1997	Koppel			
	AC	5,923,720	Jul. 1999	Barton, et al.			
	AD	6,512,814	01-2003	Yokhin, et al.			
	AE	2001/0043668	11-2001	Hayashi, et al.			

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	AA	2001/0028699	10-2001	Iwasaki			
	AB	6,381,303	04-2002	Vu, et al.			
	AC	6,389,102	05-2002	Mazor, et al.			
	AD	5,574,284	11-1996	Farr			
	AE	5,151,588	09-1992	Kiri, et al.			
	AF	4,725,963	02-1988	Taylor, et al.			

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<del>AB</del>	<del>6,381,303</del>	<del>04-2002</del>	<del>Vu, et al.</del>				
<del>AC</del>	<del>6,389,102</del>	<del>05-2002</del>	<del>Mazor, et al.</del>				
<del>AD</del>	<del>5,574,284</del>	<del>11-1996</del>	<del>Fan</del>				
<del>AE</del>	<del>5,151,388</del>	<del>09-1992</del>	<del>Kiri, et al.</del>				
<del>AF</del>	<del>4,725,963</del>	<del>02-1988</del>	<del>Taylor, et al.</del>				

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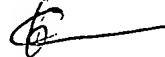
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<del>AJ</del>	<del>Ito, "X-ray Scattering Method for Determining Pore-Size Distribution in Low-k Thin Films", Presented at the International Sematech Ultra-Low-k Workshop (San Francisco, CA, June 6-7, 2002).</del>
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	FILING DATE October 20, 2003	GROUP ART UNIT 2882

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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>K</i>	AA	6,744,950	06-2004	Aleksoff			
	AB	6,643,354	11-2003	Koppel, et al.			
	AC	6,507,634	01-2003	Koppel, et al.			
	AD	6,453,006	09-2002	Koppel, et al.			
	AE	2004/0052330	03-2004	Koppel, et al.			
	AF	2002/0110218	08-2002	Koppel, et al.			
	AG	2002/0097837	07-2002	Fanton, et al.			
<i>K</i>	AH	6,711,232	03-2004	Janik			

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		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB	TRANS- LATION
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## OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION STATEMENT	APPLICANT David BERMAN, et al.	EXAMINER <del>(N/A)</del> K90
	FILING DATE October 20, 2003	GROUP ART UNIT 2882

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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
<i>[initials]</i>	AA	6,771,735	08-2004	Janik, et al.			
	AB	2003/0157559	08-2003	Omote, et al.			
	AC	6,192,103	02-2001	Wormington, et al.			
<i>[initials]</i>	AD	5,949,847	09-1999	Terada, et al.			
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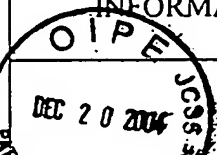
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






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	AA	2004/0218717	11-2004	Koppel, et al.			
	AB	6,813,338	11-2004	Takata, et al.			
	AC						

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